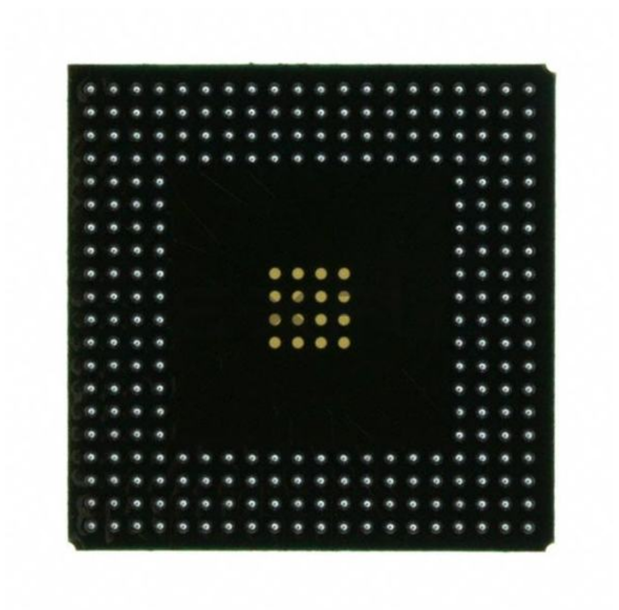

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	576
Number of Logic Elements/Cells	1368
Total RAM Bits	18432
Number of I/O	192
Number of Gates	30000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	256-BBGA
Supplier Device Package	256-PBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcs30-4bg256c

Spartan and Spartan-XL devices provide system clock rates exceeding 80 MHz and internal performance in excess of 150 MHz. In addition to the conventional benefit of high volume programmable logic solutions, Spartan series FPGAs also offer on-chip edge-triggered single-port and dual-port RAM, clock enables on all flip-flops, fast carry logic, and many other features.

The Spartan/XL families leverage the highly successful XC4000 architecture with many of that family's features and benefits. Technology advancements have been derived from the XC4000XLA process developments.

Logic Functional Description

The Spartan series uses a standard FPGA structure as shown in Figure 1, page 2. The FPGA consists of an array of configurable logic blocks (CLBs) placed in a matrix of routing channels. The input and output of signals is achieved through a set of input/output blocks (IOBs) forming a ring around the CLBs and routing channels.

- CLBs provide the functional elements for implementing the user's logic.
- IOBs provide the interface between the package pins and internal signal lines.
- Routing channels provide paths to interconnect the inputs and outputs of the CLBs and IOBs.

The functionality of each circuit block is customized during configuration by programming internal static memory cells. The values stored in these memory cells determine the logic functions and interconnections implemented in the FPGA.

Configurable Logic Blocks (CLBs)

The CLBs are used to implement most of the logic in an FPGA. The principal CLB elements are shown in the simplified block diagram in Figure 2. There are three look-up tables (LUT) which are used as logic function generators, two flip-flops and two groups of signal steering multiplexers. There are also some more advanced features provided by the CLB which will be covered in the **Advanced Features Description**, page 13.

Function Generators

Two 16 x 1 memory look-up tables (F-LUT and G-LUT) are used to implement 4-input function generators, each offering unrestricted logic implementation of any Boolean function of up to four independent input signals (F1 to F4 or G1 to G4). Using memory look-up tables the propagation delay is independent of the function implemented.

A third 3-input function generator (H-LUT) can implement any Boolean function of its three inputs. Two of these inputs are controlled by programmable multiplexers (see box "A" of Figure 2). These inputs can come from the F-LUT or G-LUT outputs or from CLB inputs. The third input always comes from a CLB input. The CLB can, therefore, implement certain functions of up to nine inputs, like parity checking. The three LUTs in the CLB can also be combined to do any arbitrarily defined Boolean function of five inputs.

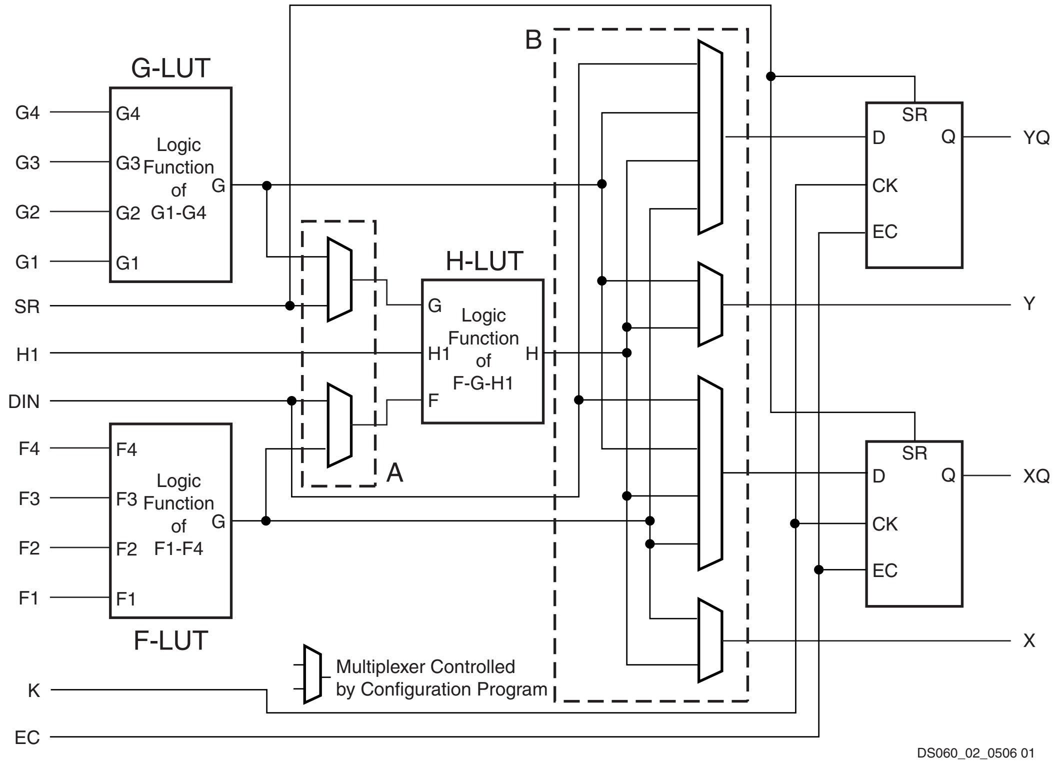


Figure 2: **Spartan/XL Simplified CLB Logic Diagram (some features not shown)**

A CLB can implement any of the following functions:

- Any function of up to four variables, plus any second function of up to four unrelated variables, plus any third function of up to three unrelated variables

  Note: When three separate functions are generated, one of the function outputs must be captured in a flip-flop internal to the CLB. Only two unregistered function generator outputs are available from the CLB.
- Any single function of five variables
- Any function of four variables together with some functions of six variables
- Some functions of up to nine variables.

Implementing wide functions in a single block reduces both the number of blocks required and the delay in the signal path, achieving both increased capacity and speed.

The versatility of the CLB function generators significantly improves system speed. In addition, the design-software tools can deal with each function generator independently. This flexibility improves cell usage.

Flip-Flops

Each CLB contains two flip-flops that can be used to register (store) the function generator outputs. The flip-flops and function generators can also be used independently (see Figure 2). The CLB input DIN can be used as a direct input to either of the two flip-flops. H1 can also drive either flip-flop via the H-LUT with a slight additional delay.

The two flip-flops have common clock (CK), clock enable (EC) and set/reset (SR) inputs. Internally both flip-flops are also controlled by a global initialization signal (GSR) which is described in detail in **Global Signals: GSR and GTS, page 20**.

Latches (Spartan-XL Family Only)

The Spartan-XL family CLB storage elements can also be configured as latches. The two latches have common clock (K) and clock enable (EC) inputs. Functionality of the storage element is described in Table 2.

Table 2: **CLB Storage Element Functionality**

Mode	CK	EC	SR	D	Q
Power-Up or GSR	X	X	X	X	SR
Flip-Flop Operation	X	X	1	X	SR
	_/‾	1*	0*	D	D
	0	X	0*	X	Q
Latch Operation (Spartan-XL)	1	1*	0*	X	Q
	0	1*	0*	D	D
Both	X	0	0*	X	Q

Legend:

X	Don't care
_/‾	Rising edge (clock not inverted).
SR	Set or Reset value. Reset is default.
0*	Input is Low or unconnected (default value)
1*	Input is High or unconnected (default value)

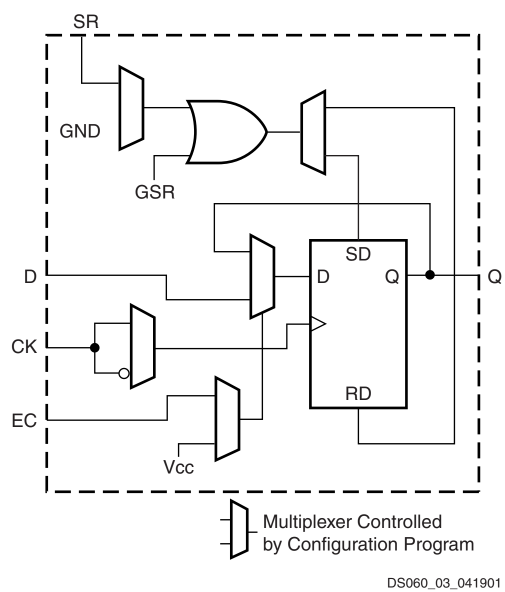


Figure 3: **CLB Flip-Flop Functional Block Diagram**

Clock Input

Each flip-flop can be triggered on either the rising or falling clock edge. The CLB clock line is shared by both flip-flops. However, the clock is individually invertible for each flip-flop (see CK path in Figure 3). Any inverter placed on the clock line in the design is automatically absorbed into the CLB.

Clock Enable

The clock enable line (EC) is active High. The EC line is shared by both flip-flops in a CLB. If either one is left disconnected, the clock enable for that flip-flop defaults to the active state. EC is not invertible within the CLB. The clock enable is synchronous to the clock and must satisfy the setup and hold timing specified for the device.

Set/Reset

The set/reset line (SR) is an asynchronous active High control of the flip-flop. SR can be configured as either set or reset at each flip-flop. This configuration option determines the state in which each flip-flop becomes operational after configuration. It also determines the effect of a GSR pulse during normal operation, and the effect of a pulse on the SR line of the CLB. The SR line is shared by both flip-flops. If SR is not specified for a flip-flop the set/reset for that flip-flop defaults to the inactive state. SR is not invertible within the CLB.

CLB Signal Flow Control

In addition to the H-LUT input control multiplexers (shown in box "A" of Figure 2, page 4) there are signal flow control multiplexers (shown in box "B" of Figure 2) which select the signals which drive the flip-flop inputs and the combinatorial CLB outputs (X and Y).

Each flip-flop input is driven from a 4:1 multiplexer which selects among the three LUT outputs and DIN as the data source.

Each combinatorial output is driven from a 2:1 multiplexer which selects between two of the LUT outputs. The X output can be driven from the F-LUT or H-LUT, the Y output from G-LUT or H-LUT.

Control Signals

There are four signal control multiplexers on the input of the CLB. These multiplexers allow the internal CLB control signals (H1, DIN, SR, and EC in Figure 2 and Figure 4) to be driven from any of the four general control inputs (C1-C4 in Figure 4) into the CLB. Any of these inputs can drive any of the four internal control signals.

Figure 20 is a diagram of the Spartan/XL FPGA boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

Spartan/XL devices can also be configured through the boundary scan logic. See **Configuration Through the Boundary Scan Pins**, page 37.

Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out and 3-state Control. Non-IOB pins have appropriate partial bit population for In or Out only. PROGRAM, CCLK and DONE are not included in the boundary scan register. Each EXTEST CAPTURE-DR state captures all In, Out, and 3-state pins.

The data register also includes the following non-pin bits: TDO.T, and TDO.O, which are always bits 0 and 1 of the data register, respectively, and BSCANT.UPD, which is always the last bit of the data register. These three boundary scan bits are special-purpose Xilinx test signals.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA provides two additional data registers that can be specified using the BSCAN macro. The FPGA provides two user pins (BSCAN.SEL1 and BSCAN.SEL2) which are the decodes of two user instructions. For these instructions, two corresponding pins (BSCAN.TDO1 and BSCAN.TDO2) allow user scan data to be shifted out on TDO. The data register clock (BSCAN.DRCK) is available for control of test logic which the user may wish to implement with CLBs. The NAND of TCK and RUN-TEST-IDLE is also provided (BSCAN.IDLE).

Instruction Set

The Spartan/XL FPGA boundary scan instruction set also includes instructions to configure the device and read back the configuration data. The instruction set is coded as shown in Table 12.

Table 12: **Boundary Scan Instructions**

Instruction			Test Selected	TDO Source	I/O Data Source
I2	I1	I0			
0	0	0	EXTEST	DR	DR
0	0	1	SAMPLE/ PRELOAD	DR	Pin/Logic
0	1	0	USER 1	BSCAN. TDO1	User Logic
0	1	1	USER 2	BSCAN. TDO2	User Logic
1	0	0	READBACK	Readback Data	Pin/Logic
1	0	1	CONFIGURE	DOUT	Disabled
1	1	0	IDCODE (Spartan-XL only)	IDCODE Register	-
1	1	1	BYPASS	Bypass Register	-

Bit Sequence

The bit sequence within each IOB is: In, Out, 3-state. The input-only pins contribute only the In bit to the boundary scan I/O data register, while the output-only pins contributes all three bits.

The first two bits in the I/O data register are TDO.T and TDO.O, which can be used for the capture of internal signals. The final bit is BSCANT.UPD, which can be used to drive an internal net. These locations are primarily used by Xilinx for internal testing.

From a cavity-up view of the chip (as shown in the FPGA Editor), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in Figure 21. The device-specific pinout tables for the Spartan/XL devices include the boundary scan locations for each IOB pin.

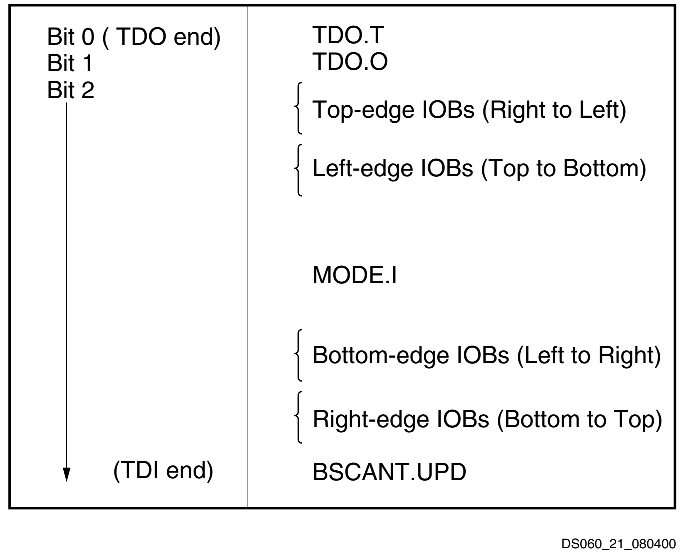


Figure 21: **Boundary Scan Bit Sequence**

BSDL (Boundary Scan Description Language) files for Spartan/XL devices are available on the Xilinx website in the File Download area. Note that the 5V Spartan devices and 3V Spartan-XL devices have different BSDL files.

Including Boundary Scan in a Design

If boundary scan is only to be used during configuration, no special elements need be included in the schematic or HDL code. In this case, the special boundary scan pins TDI, TMS, TCK and TDO can be used for user functions after configuration.

To indicate that boundary scan remain enabled after configuration, place the BSCAN library symbol and connect the TDI, TMS, TCK and TDO pad symbols to the appropriate pins, as shown in Figure 22.

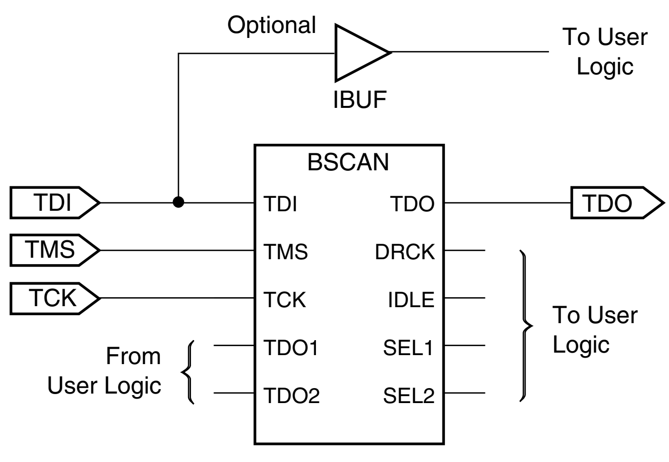


Figure 22: **Boundary Scan Example**

Table 16: **Spartan/XL Data Stream Formats**

Data Type	Serial Modes (D0...)	Express Mode (D0-D7) (Spartan-XL only)
Fill Byte	11111111b	FFFFh
Preamble Code	0010b	11110010b
Length Count	COUNT[23:0]	COUNT[23:0](1)
Fill Bits	1111b	-
Field Check Code	-	11010010b
Start Field	0b	11111110b(2)
Data Frame	DATA[n–1:0]	DATA[n–1:0]
CRC or Constant Field Check	xxxx (CRC) or 0110b	11010010b
Extend Write Cycle	-	FFD2FFFFFFh
Postamble	01111111b	-
Start-Up Bytes(3)	FFh	FFFFFFFFFFFFFFh

Legend:

Unshaded	Once per bitstream
Light	Once per data frame
Dark	Once per device

Notes:
1. Not used by configuration logic.
2. 11111111b for XCS40XL only.
3. Development system may add more start-up bytes.

A selection of CRC or non-CRC error checking is allowed by the bitstream generation software. The Spartan-XL family Express mode only supports non-CRC error checking. The non-CRC error checking tests for a designated end-of-frame field for each frame. For CRC error checking, the software calculates a running CRC and inserts a unique four-bit partial check at the end of each frame. The 11-bit CRC check of the last frame of an FPGA includes the last seven data bits.

Detection of an error results in the suspension of data loading before DONE goes High, and the pulling down of the $\overline{\text{INIT}}$ pin. In Master serial mode, CCLK continues to operate externally. The user must detect $\overline{\text{INIT}}$ and initialize a new configuration by pulsing the $\overline{\text{PROGRAM}}$ pin Low or cycling V_{CC}.

Cyclic Redundancy Check (CRC) for Configuration and Readback

The Cyclic Redundancy Check is a method of error detection in data transmission applications. Generally, the transmitting system performs a calculation on the serial bitstream. The result of this calculation is tagged onto the data stream as additional check bits. The receiving system performs an identical calculation on the bitstream and compares the result with the received checksum.

Each data frame of the configuration bitstream has four error bits at the end, as shown in Table 16. If a frame data error is detected during the loading of the FPGA, the configuration process with a potentially corrupted bitstream is terminated. The FPGA pulls the $\overline{\text{INIT}}$ pin Low and goes into a Wait state.

Table 17: **Spartan/XL Program Data**

Device	XCS05		XCS10		XCS20		XCS30		XCS40	
Max System Gates	5,000		10,000		20,000		30,000		40,000	
CLBs (Row x Col.)	100 (10 x 10)		196 (14 x 14)		400 (20 x 20)		576 (24 x 24)		784 (28 x 28)	
IOBs	80		112		160		192		205(4)	
Part Number	XCS05	XCS05XL	XCS10	XCS10XL	XCS20	XCS20XL	XCS30	XCS30XL	XCS40	XCS40XL
Supply Voltage	5V	3.3V	5V	3.3V	5V	3.3V	5V	3.3V	5V	3.3V
Bits per Frame	126	127	166	167	226	227	266	267	306	307
Frames	428	429	572	573	788	789	932	933	1,076	1,077
Program Data	53,936	54,491	94,960	95,699	178,096	179,111	247,920	249,119	329,264	330,647
PROM Size (bits)	53,984	54,544	95,008	95,752	178,144	179,160	247,968	249,168	329,312	330,696
Express Mode PROM Size (bits)	-	79,072	-	128,488	-	221,056	-	298,696	-	387,856

Notes:
1. Bits per Frame = (10 x number of rows) + 7 for the top + 13 for the bottom + 1 + 1 start bit + 4 error check bits (+1 for Spartan-XL device)
   Number of Frames = (36 x number of columns) + 26 for the left edge + 41 for the right edge + 1 (+ 1 for Spartan-XL device)
   Program Data = (Bits per Frame x Number of Frames) + 8 postamble bits
   PROM Size = Program Data + 40 (header) + 8, rounded up to the nearest byte
2. The user can add more "1" bits as leading dummy bits in the header, or, if CRC = off, as trailing dummy bits at the end of any frame, following the four error check bits. However, the Length Count value **must** be adjusted for all such extra "one" bits, even for extra leading ones at the beginning of the header.
3. Express mode adds 57 (XCS05XL, XCS10XL), or 53 (XCS20XL, XCS30XL, XCS40XL) bits per frame, + additional start-up bits.
4. XCS40XL provided 224 max I/O in CS280 package discontinued by **PDN2004-01**.

During Readback, 11 bits of the 16-bit checksum are added to the end of the Readback data stream. The checksum is computed using the CRC-16 CCITT polynomial, as shown in Figure 29. The checksum consists of the 11 most significant bits of the 16-bit code. A change in the checksum indicates a change in the Readback bitstream. A comparison to a previous checksum is meaningful only if the readback data is independent of the current device state. CLB outputs should not be included (Readback Capture option not used), and if RAM is present, the RAM content must be unchanged.

Statistically, one error out of 2048 might go undetected.

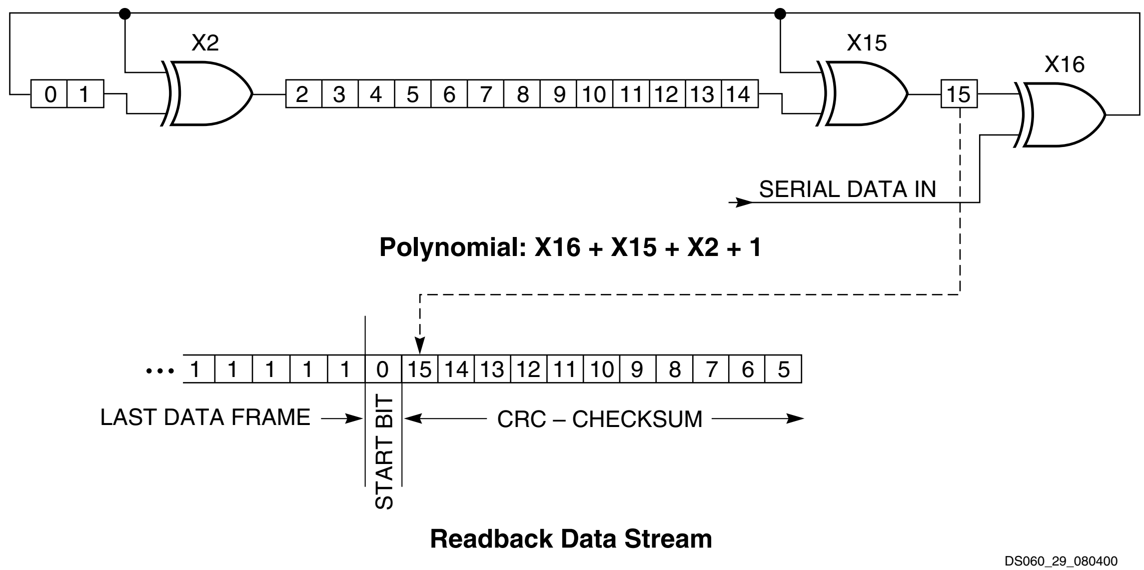


Figure 29: **Circuit for Generating CRC-16**

Configuration Sequence

There are four major steps in the Spartan/XL FPGA power-up configuration sequence.

- Configuration Memory Clear
- Initialization
- Configuration
- Start-up

The full process is illustrated in Figure 30.

Configuration Memory Clear

When power is first applied or is reapplied to an FPGA, an internal circuit forces initialization of the configuration logic. When V_{CC} reaches an operational level, and the circuit passes the write and read test of a sample pair of configuration bits, a time delay is started. This time delay is nominally 16 ms. The delay is four times as long when in Master Serial Mode to allow ample time for all slaves to reach a stable V_{CC}. When all $\overline{\text{INIT}}$ pins are tied together, as recommended, the longest delay takes precedence. Therefore, devices with different time delays can easily be mixed and matched in a daisy chain.

This delay is applied only on power-up. It is not applied when reconfiguring an FPGA by pulsing the $\overline{\text{PROGRAM}}$ pin Low. During this time delay, or as long as the $\overline{\text{PROGRAM}}$ input is asserted, the configuration logic is held in a Configuration Memory Clear state. The configuration-memory frames are consecutively initialized, using the internal oscillator.

At the end of each complete pass through the frame addressing, the power-on time-out delay circuitry and the level of the $\overline{\text{PROGRAM}}$ pin are tested. If neither is asserted, the logic initiates one additional clearing of the configuration frames and then tests the $\overline{\text{INIT}}$ input.

Initialization

During initialization and configuration, user pins HDC, $\overline{\text{LDC}}$, $\overline{\text{INIT}}$ and DONE provide status outputs for the system interface. The outputs $\overline{\text{LDC}}$, $\overline{\text{INIT}}$ and DONE are held Low and HDC is held High starting at the initial application of power.

The open drain $\overline{\text{INIT}}$ pin is released after the final initialization pass through the frame addresses. There is a deliberate delay before a Master-mode device recognizes an inactive $\overline{\text{INIT}}$. Two internal clocks after the $\overline{\text{INIT}}$ pin is recognized as High, the device samples the MODE pin to determine the configuration mode. The appropriate interface lines become active and the configuration preamble and data can be loaded.

Readback

The user can read back the content of configuration memory and the level of certain internal nodes without interfering with the normal operation of the device.

Readback not only reports the downloaded configuration bits, but can also include the present state of the device, represented by the content of all flip-flops and latches in CLBs and IOBs, as well as the content of function generators used as RAMs.

Although readback can be performed while the device is operating, for best results and to freeze a known capture state, it is recommended that the clock inputs be stopped until readback is complete.

Readback of Spartan-XL family Express mode bitstreams results in data that does not resemble the original bitstream, because the bitstream format differs from other modes.

Spartan/XL FPGA Readback does not use any dedicated pins, but uses four internal nets (RDBK.TRIG, RDBK.DATA, RDBK.RIP and RDBK.CLK) that can be routed to any IOB. To access the internal Readback signals, instantiate the READBACK library symbol and attach the appropriate pad symbols, as shown in Figure 32.

After Readback has been initiated by a Low-to-High transition on RDBK.TRIG, the RDBK.RIP (Read In Progress) output goes High on the next rising edge of RDBK.CLK. Subsequent rising edges of this clock shift out Readback data on the RDBK.DATA net.

Readback data does not include the preamble, but starts with five dummy bits (all High) followed by the Start bit (Low) of the first frame. The first two data bits of the first frame are always High.

Each frame ends with four error check bits. They are read back as High. The last seven bits of the last frame are also read back as High. An additional Start bit (Low) and an 11-bit Cyclic Redundancy Check (CRC) signature follow, before RDBK.RIP returns Low.

Readback Options

Readback options are: Readback Capture, Readback Abort, and Clock Select. They are set with the bitstream generation software.

Readback Capture

When the Readback Capture option is selected, the data stream includes sampled values of CLB and IOB signals. The rising edge of RDBK.TRIG latches the inverted values of the four CLB outputs, the IOB output flip-flops and the input signals I1 and I2. Note that while the bits describing configuration (interconnect, function generators, and RAM content) are *not* inverted, the CLB and IOB output signals *are* inverted. RDBK.TRIG is located in the lower-left corner of the device.

When the Readback Capture option is not selected, the values of the capture bits reflect the configuration data originally written to those memory locations. If the RAM capability of the CLBs is used, RAM data are available in Readback, since they directly overwrite the F and G function-table configuration of the CLB.

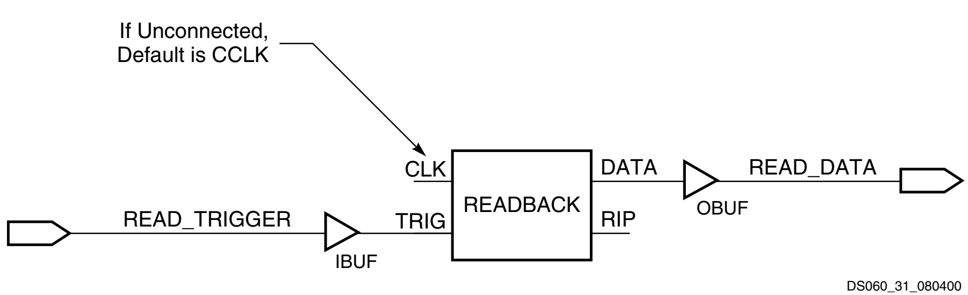


Figure 32: **Readback Example**

Readback Abort

When the Readback Abort option is selected, a High-to-Low transition on RDBK.TRIG terminates the Readback operation and prepares the logic to accept another trigger.

After an aborted Readback, additional clocks (up to one Readback clock per configuration frame) may be required to re-initialize the control logic. The status of Readback is indicated by the output control net RDBK.RIP. RDBK.RIP is High whenever a readback is in progress.

Clock Select

CCLK is the default clock. However, the user can insert another clock on RDBK.CLK. Readback control and data are clocked on rising edges of RDBK.CLK. If Readback must be inhibited for security reasons, the Readback control nets are simply not connected. RDBK.CLK is located in the lower right chip corner.

Violating the Maximum High and Low Time Specification for the Readback Clock

The Readback clock has a maximum High and Low time specification. In some cases, this specification cannot be met. For example, if a processor is controlling Readback, an interrupt may force it to stop in the middle of a readback. This necessitates stopping the clock, and thus violating the specification.

The specification is mandatory only on clocking data at the end of a frame prior to the next start bit. The transfer mechanism will load the data to a shift register during the last six clock cycles of the frame, prior to the start bit of the following frame. This loading process is dynamic, and is the source of the maximum High and Low time requirements.

Therefore, the specification only applies to the six clock cycles prior to and including any start bit, including the clocks before the first start bit in the Readback data stream. At other times, the frame data is already in the register and the register is not dynamic. Thus, it can be shifted out just like a regular shift register.

The user must precisely calculate the location of the Readback data relative to the frame. The system must keep track of the position within a data frame, and disable interrupts before frame boundaries. Frame lengths and data formats are listed in Table 16 and Table 17.

Spartan Family IOB Output Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values are expressed in nanoseconds unless otherwise noted.

Symbol	Description	Device	Speed Grade				Units
			-4		-3		
			Min	Max	Min	Max	
Clocks							
T_{CH}	Clock High	All devices	3.0	-	4.0	-	ns
T_{CL}	Clock Low	All devices	3.0	-	4.0	-	ns
Propagation Delays - TTL Outputs(1,2)							
T_{OKPOF}	Clock (OK) to Pad, fast	All devices	-	3.3	-	4.5	ns
T_{OKPOS}	Clock (OK to Pad, slew-rate limited	All devices	-	6.9	-	7.0	ns
T_{OPF}	Output (O) to Pad, fast	All devices	-	3.6	-	4.8	ns
T_{OPS}	Output (O) to Pad, slew-rate limited	All devices	-	7.2	-	7.3	ns
T_{TSHZ}	3-state to Pad High-Z (slew-rate independent)	All devices	-	3.0	-	3.8	ns
T_{TSONF}	3-state to Pad active and valid, fast	All devices	-	6.0	-	7.3	ns
T_{TSONS}	3-state to Pad active and valid, slew-rate limited	All devices	-	9.6	-	9.8	ns
Setup and Hold Times							
T_{OOK}	Output (O) to clock (OK) setup time	All devices	2.5	-	3.8	-	ns
T_{OKO}	Output (O) to clock (OK) hold time	All devices	0.0	-	0.0	-	ns
T_{ECOK}	Clock Enable (EC) to clock (OK) setup time	All devices	2.0	-	2.7	-	ns
T_{OKEC}	Clock Enable (EC) to clock (OK) hold time	All devices	0.0	-	0.5	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	11.5		13.5		ns
T_{RPO}	Delay from GSR input to any Pad	XCS05	-	12.0	-	15.0	ns
		XCS10	-	12.5	-	15.7	ns
		XCS20	-	13.0	-	16.2	ns
		XCS30	-	13.5	-	16.9	ns
		XCS40	-	14.0	-	17.5	ns

Notes:
1. Delay adder for CMOS Outputs option (with fast slew rate option): for -3 speed grade, add 1.0 ns; for -4 speed grade, add 0.8 ns.
2. Delay adder for CMOS Outputs option (with slow slew rate option): for -3 speed grade, add 2.0 ns; for -4 speed grade, add 1.5 ns.
3. Output timing is measured at ~50% V_{CC} threshold, with 50 pF external capacitive loads including test fixture. Slew-rate limited output rise/fall times are approximately two times longer than fast output rise/fall times.
4. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Spartan-XL Family Global Buffer Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

When fewer vertical clock lines are connected, the clock distribution is faster; when multiple clock lines per column are driven from the same global clock, the delay is longer. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade		Units
			-5	-4	
			Max	Max	
T_{GLS}	From pad through buffer, to any clock K	XCS05XL	1.4	1.5	ns
		XCS10XL	1.7	1.8	ns
		XCS20XL	2.0	2.1	ns
		XCS30XL	2.3	2.5	ns
		XCS40XL	2.6	2.8	ns

Spartan-XL Family CLB Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-XL devices and expressed in nanoseconds unless otherwise noted.

Symbol	Description	Speed Grade				Units
		-5		-4		
		Min	Max	Min	Max	
Clocks						
T_{CH}	Clock High time	2.0	-	2.3	-	ns
T_{CL}	Clock Low time	2.0	-	2.3	-	ns
Combinatorial Delays						
T_{ILO}	F/G inputs to X/Y outputs	-	1.0	-	1.1	ns
T_{IHO}	F/G inputs via H to X/Y outputs	-	1.7	-	2.0	ns
T_{ITO}	F/G inputs via transparent latch to Q outputs	-	1.5	-	1.8	ns
T_{HH1O}	C inputs via H1 via H to X/Y outputs	-	1.5	-	1.8	ns
Sequential Delays						
T_{CKO}	Clock K to Flip-Flop or latch outputs Q	-	1.2	-	1.4	ns
Setup Time before Clock K						
T_{ICK}	F/G inputs	0.6	-	0.7	-	ns
T_{IHCK}	F/G inputs via H	1.3	-	1.6	-	ns
Hold Time after Clock K						
	All Hold times, all devices	0.0	-	0.0	-	ns
Set/Reset Direct						
T_{RPW}	Width (High)	2.5	-	2.8	-	ns
T_{RIO}	Delay from C inputs via S/R, going High to Q	-	2.3	-	2.7	ns
Global Set/Reset						
T_{MRW}	Minimum GSR Pulse Width	10.5	-	11.5	-	ns
T_{MRQ}	Delay from GSR input to any Q	See page 60 for T_{RRI} values per device.				
F_{TOG}	Toggle Frequency (MHz) (for export control purposes)	-	250	-	217	MHz

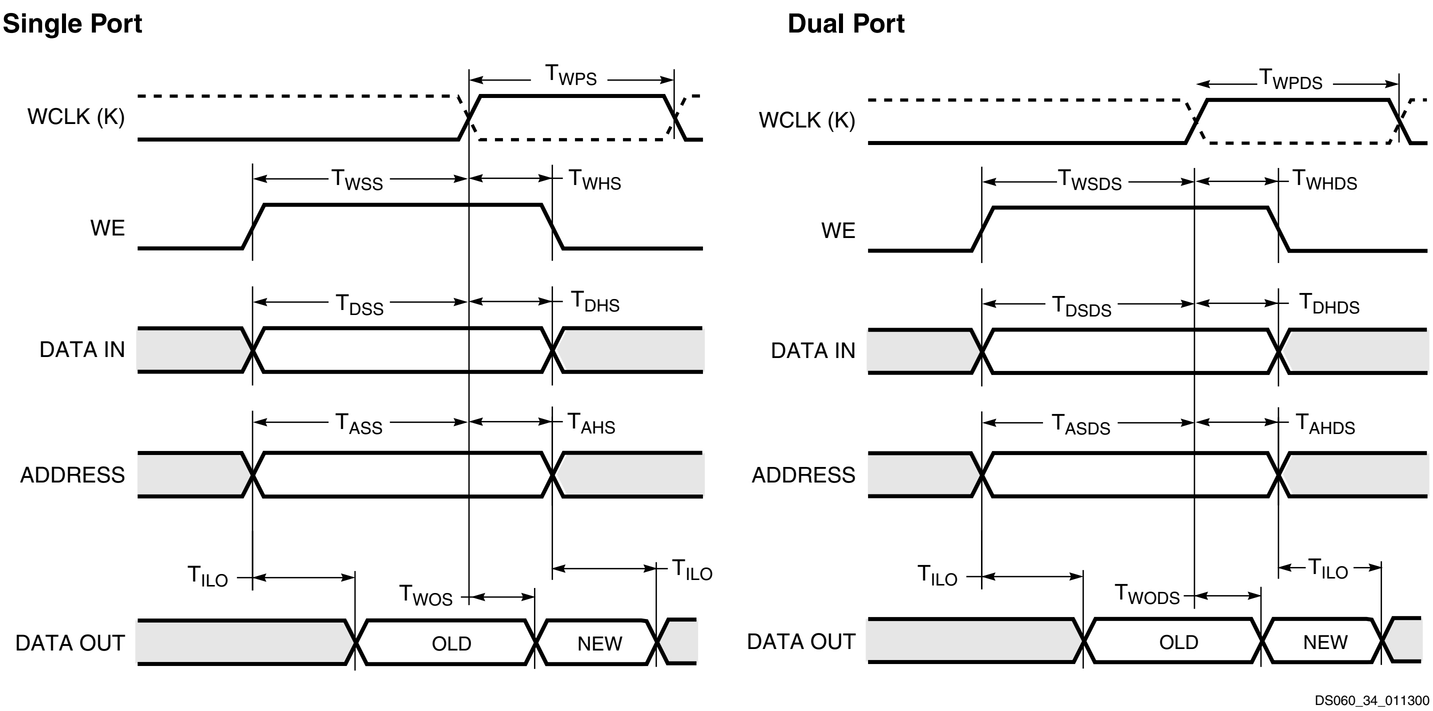
Spartan-XL Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines (cont.)

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-XL devices and are expressed in nanoseconds unless otherwise noted.

Symbol	Dual Port RAM	Size	-5		-4		Units
			Min	Max	Min	Max	
Write Operation[1]							
T_{WCDS}	Address write cycle time (clock K period)	16x1	7.7	-	8.4	-	ns
T_{WPDS}	Clock K pulse width (active edge)	16x1	3.1	-	3.6	-	ns
T_{ASDS}	Address setup time before clock K	16x1	1.3	-	1.5	-	ns
T_{DSDS}	DIN setup time before clock K	16x1	1.7	-	2.0	-	ns
T_{WSDS}	WE setup time before clock K	16x1	1.4	-	1.6	-	ns
	All hold times after clock K	16x1	0	-	0	-	ns
T_{WODS}	Data valid after clock K	16x1	-	5.2	-	6.1	ns

Notes:
1. Read Operation timing for 16 x 1 dual-port RAM option is identical to 16 x 2 single-port RAM timing

Spartan-XL Family CLB RAM Synchronous (Edge-Triggered) Write Timing



Spartan-XL Family IOB Output Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values are expressed in nanoseconds unless otherwise noted.

Symbol	Description	Device	Speed Grade -5 Min	-5 Max	-4 Min	-4 Max	Units
Propagation Delays							
T_{OKPOF}	Clock (OK) to Pad, fast	All devices	-	3.2	-	3.7	ns
T_{OPF}	Output (O) to Pad, fast	All devices	-	2.5	-	2.9	ns
T_{TSHZ}	3-state to Pad High-Z (slew-rate independent)	All devices	-	2.8	-	3.3	ns
T_{TSONF}	3-state to Pad active and valid, fast	All devices	-	2.6	-	3.0	ns
T_{OFPF}	Output (O) to Pad via Output MUX, fast	All devices	-	3.7	-	4.4	ns
T_{OKFPF}	Select (OK) to Pad via Output MUX, fast	All devices	-	3.3	-	3.9	ns
T_{SLOW}	For Output SLOW option add	All devices	-	1.5	-	1.7	ns
Setup and Hold Times							
T_{OOK}	Output (O) to clock (OK) setup time	All devices	0.5	-	0.5	-	ns
T_{OKO}	Output (O) to clock (OK) hold time	All devices	0.0	-	0.0	-	ns
T_{ECOK}	Clock Enable (EC) to clock (OK) setup time	All devices	0.0	-	0.0	-	ns
T_{OKEC}	Clock Enable (EC) to clock (OK) hold time	All devices	0.1	-	0.2	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	10.5	-	11.5	-	ns
T_{RPO}	Delay from GSR input to any Pad	XCS05XL	-	11.9	-	14.0	ns
		XCS10XL	-	12.4	-	14.5	ns
		XCS20XL	-	12.9	-	15.0	ns
		XCS30XL	-	13.9	-	16.0	ns
		XCS40XL	-	14.9	-	17.0	ns

Notes:
1. Output timing is measured at ~50% V_{CC} threshold, with 50 pF external capacitive loads including test fixture. Slew-rate limited output rise/fall times are approximately two times longer than fast output rise/fall times.
2. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Pin Descriptions

There are three types of pins in the Spartan/XL devices:

- Permanently dedicated pins
- User I/O pins that can have special functions
- Unrestricted user-programmable I/O pins.

Before and during configuration, all outputs not used for the configuration process are 3-stated with the I/O pull-up resistor network activated. After configuration, if an IOB is unused it is configured as an input with the I/O pull-up resistor network remaining activated.

Any user I/O can be configured to drive the Global Set/Reset net GSR or the global three-state net GTS. See **Global Signals: GSR and GTS**, page 20 for more information.

Device pins for Spartan/XL devices are described in Table 18.

Some Spartan-XL devices are available in Pb-free package options. The Pb-free package options have the same pinouts as the standard package options.

Table 18: **Pin Descriptions**

Pin Name	I/O During Config.	I/O After Config.	Pin Description
Permanently Dedicated Pins			
V_{CC}	X	X	Eight or more (depending on package) connections to the nominal +5V supply voltage (+3.3V for Spartan-XL devices). All must be connected, and each must be decoupled with a 0.01 –0.1 µF capacitor to Ground.
GND	X	X	Eight or more (depending on package type) connections to Ground. All must be connected.
CCLK	I or O	I	During configuration, Configuration Clock (CCLK) is an output in Master mode and is an input in Slave mode. After configuration, CCLK has a weak pull-up resistor and can be selected as the Readback Clock. There is no CCLK High or Low time restriction on Spartan/XL devices, except during Readback. See **Violating the Maximum High and Low Time Specification for the Readback Clock**, page 39 for an explanation of this exception.
DONE	I/O	O	DONE is a bidirectional signal with an optional internal pull-up resistor. As an open-drain output, it indicates the completion of the configuration process. As an input, a Low level on DONE can be configured to delay the global logic initialization and the enabling of outputs. The optional pull-up resistor is selected as an option in the program that creates the configuration bitstream. The resistor is included by default.
$\overline{\text{PROGRAM}}$	I	I	$\overline{\text{PROGRAM}}$ is an active Low input that forces the FPGA to clear its configuration memory. It is used to initiate a configuration cycle. When $\overline{\text{PROGRAM}}$ goes High, the FPGA finishes the current clear cycle and executes another complete clear cycle, before it goes into a WAIT state and releases $\overline{\text{INIT}}$. The $\overline{\text{PROGRAM}}$ pin has a permanent weak pull-up, so it need not be externally pulled up to VCC.
MODE (Spartan) M0, M1 (Spartan-XL)	I	X	The Mode input(s) are sampled after $\overline{\text{INIT}}$ goes High to determine the configuration mode to be used. During configuration, these pins have a weak pull-up resistor. For the most popular configuration mode, Slave Serial, the mode pins can be left unconnected. For Master Serial mode, connect the Mode/M0 pin directly to system ground.

Table 18: **Pin Descriptions *(Continued)***

Pin Name	I/O During Config.	I/O After Config.	Pin Description
PWRDWN	I	I	PWRDWN is an active Low input that forces the FPGA into the Power Down state and reduces power consumption. When PWRDWN is Low, the FPGA disables all I/O and initializes all flip-flops. All inputs are interpreted as Low independent of their actual level. VCC must be maintained, and the configuration data is maintained. PWRDWN halts configuration if asserted before or during configuration, and re-starts configuration when removed. When PWRDWN returns High, the FPGA becomes operational by first enabling the inputs and flip-flops and then enabling the outputs. PWRDWN has a default internal pull-up resistor.
User I/O Pins That Can Have Special Functions			
TDO	O	O	If boundary scan is used, this pin is the Test Data Output. If boundary scan is not used, this pin is a 3-state output without a register, after configuration is completed. To use this pin, place the library component TDO instead of the usual pad symbol. An output buffer must still be used.
TDI, TCK, TMS	I	I/O or I (JTAG)	If boundary scan is used, these pins are Test Data In, Test Clock, and Test Mode Select inputs respectively. They come directly from the pads, bypassing the IOBs. These pins can also be used as inputs to the CLB logic after configuration is completed. If the BSCAN symbol is not placed in the design, all boundary scan functions are inhibited once configuration is completed, and these pins become user-programmable I/O. In this case, they must be called out by special library elements. To use these pins, place the library components TDI, TCK, and TMS instead of the usual pad symbols. Input or output buffers must still be used.
HDC	O	I/O	High During Configuration (HDC) is driven High until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, HDC is a user-programmable I/O pin.
LDC	O	I/O	Low During Configuration (LDC) is driven Low until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, LDC is a user-programmable I/O pin.
INIT	I/O	I/O	Before and during configuration, INIT is a bidirectional signal. A 1 kΩ to 10 kΩ external pull-up resistor is recommended. As an active Low open-drain output, INIT is held Low during the power stabilization and internal clearing of the configuration memory. As an active Low input, it can be used to hold the FPGA in the internal WAIT state before the start of configuration. Master mode devices stay in a WAIT state an additional 30 to 300 μs after INIT has gone High. During configuration, a Low on this output indicates that a configuration data error has occurred. After the I/O go active, INIT is a user-programmable I/O pin.
PGCK1 - PGCK4 (Spartan)	Weak Pull-up	I or I/O	Four Primary Global inputs each drive a dedicated internal global net with short delay and minimal skew. If not used to drive a global buffer, any of these pins is a user-programmable I/O. The PGCK1-PGCK4 pins drive the four Primary Global Buffers. Any input pad symbol connected directly to the input of a BUFGP symbol is automatically placed on one of these pins.

XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84(4)	VQ100	CS144(2,4)	TQ144	Bndry Scan
VCC	P33	P25	N1	P37	-
Not Connect-ed(1) PWRDWN(2)	P34	P26	N2	P38	174 (1)
I/O, PGCK2(1) GCK3(2)	P35	P27	M3	P39	175(3)
I/O (HDC)	P36	P28	N3	P40	178 (3)
I/O	-	-	K4	P41	181 (3)
I/O	-	-	L4	P42	184 (3)
I/O	-	P29	M4	P43	187 (3)
I/O (LDC)	P37	P30	N4	P44	190 (3)
GND	-	-	K5	P45	-
I/O	-	-	L5	P46	193 (3)
I/O	-	-	M5	P47	196 (3)
I/O	P38	P31	N5	P48	199 (3)
I/O	P39	P32	K6	P49	202 (3)
I/O	-	P33	L6	P50	205 (3)
I/O	-	P34	M6	P51	208 (3)
I/O	P40	P35	N6	P52	211 (3)
I/O (INIT)	P41	P36	M7	P53	214 (3)
VCC	P42	P37	N7	P54	-
GND	P43	P38	L7	P55	-
I/O	P44	P39	K7	P56	217 (3)
I/O	P45	P40	N8	P57	220 (3)
I/O	-	P41	M8	P58	223 (3)
I/O	-	P42	L8	P59	226 (3)
I/O	P46	P43	K8	P60	229 (3)
I/O	P47	P44	N9	P61	232 (3)
I/O	-	-	M9	P62	235 (3)
I/O	-	-	L9	P63	238 (3)
GND	-	-	K9	P64	-
I/O	P48	P45	N10	P65	241 (3)
I/O	P49	P46	M10	P66	244 (3)
I/O	-	-	L10	P67	247 (3)
I/O	-	-	N11	P68	250 (3)
I/O	P50	P47	M11	P69	253 (3)
I/O, SGCK3(1) GCK4(2)	P51	P48	L11	P70	256 (3)
GND	P52	P49	N12	P71	-
DONE	P53	P50	M12	P72	-
VCC	P54	P51	N13	P73	-
PROGRAM	P55	P52	M13	P74	-
I/O (D7(2))	P56	P53	L12	P75	259 (3)

XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84(4)	VQ100	CS144(2,4)	TQ144	Bndry Scan
I/O, PGCK3(1) GCK5(2)	P57	P54	L13	P76	262 (3)
I/O	-	-	K10	P77	265 (3)
I/O	-	-	K11	P78	268 (3)
I/O (D6(2))	P58	P55	K12	P79	271 (3)
I/O	-	P56	K13	P80	274 (3)
GND	-	-	J10	P81	-
I/O	-	-	J11	P82	277 (3)
I/O	-	-	J12	P83	280 (3)
I/O (D5(2))	P59	P57	J13	P84	283 (3)
I/O	P60	P58	H10	P85	286 (3)
I/O	-	P59	H11	P86	289 (3)
I/O	-	P60	H12	P87	292 (3)
I/O (D4(2))	P61	P61	H13	P88	295 (3)
I/O	P62	P62	G12	P89	298 (3)
VCC	P63	P63	G13	P90	-
GND	P64	P64	G11	P91	-
I/O (D3(2))	P65	P65	G10	P92	301 (3)
I/O	P66	P66	F13	P93	304 (3)
I/O	-	P67	F12	P94	307 (3)
I/O	-	-	F11	P95	310 (3)
I/O (D2(2))	P67	P68	F10	P96	313 (3)
I/O	P68	P69	E13	P97	316 (3)
I/O	-	-	E12	P98	319 (3)
I/O	-	-	E11	P99	322 (3)
GND	-	-	E10	P100	-
I/O (D1(2))	P69	P70	D13	P101	325 (3)
I/O	P70	P71	D12	P102	328 (3)
I/O	-	-	D11	P103	331 (3)
I/O	-	-	C13	P104	334 (3)
I/O (D0(2), DIN)	P71	P72	C12	P105	337 (3)
I/O, SGCK4(1) GCK6(2) (DOUT)	P72	P73	C11	P106	340 (3)
CCLK	P73	P74	B13	P107	-
VCC	P74	P75	B12	P108	-
O, TDO	P75	P76	A13	P109	0
GND	P76	P77	A12	P110	-
I/O	P77	P78	B11	P111	2
I/O, PGCK4(1) GCK7(2)	P78	P79	A11	P112	5
I/O	-	-	D10	P113	8
I/O	-	-	C10	P114	11
I/O (CS1(2))	P79	P80	B10	P115	14

XCS30 and XCS30XL Device Pinouts *(Continued)*

XCS30/XL Pad Name	VQ100(5)	TQ144	PQ208	PQ240	BG256(5)	CS280(2,5)	Bndry Scan
I/O	P18	P28	P44	P52	V1	T1	272
I/O	P19	P29	P45	P53	T4	T2	275
I/O	-	P30	P46	P54	U3	T3	278
I/O	-	P31	P47	P55	V2	U1	281
I/O	P20	P32	P48	P56	W1	V1	284
I/O, SGCK2(1), GCK2(2)	P21	P33	P49	P57	V3	U2	287
Not Connected(1), M1(2)	P22	P34	P50	P58	W2	V2	290
GND	P23	P35	P51	P59	GND(4)	GND(4)	-
MODE(1), M0(2)	P24	P36	P52	P60	Y1	W1	293
VCC	P25	P37	P53	P61	VCC(4)	U3	-
Not Connected (1), $\overline{\text{PWRDWN}}$(2)	P26	P38	P54	P62	W3	V3	294 (1)
I/O, PGCK2(1), GCK3(2)	P27	P39	P55	P63	Y2	W2	295 (3)
I/O (HDC)	P28	P40	P56	P64	W4	W3	298 (3)
I/O	-	P41	P57	P65	V4	T4	301 (3)
I/O	-	P42	P58	P66	U5	U4	304 (3)
I/O	P29	P43	P59	P67	Y3	V4	307 (3)
I/O ($\overline{\text{LDC}}$)	P30	P44	P60	P68	Y4	W4	310 (3)
I/O	-	-	P61	P69	V5	T5	313 (3)
I/O	-	-	P62	P70	W5	W5	316 (3)
I/O	-	-	P63	P71	Y5	R6	319 (3)
I/O	-	-	P64	P72	V6	U6	322 (3)
I/O	-	-	P65	P73	W6	V6	325 (3)
I/O	-	-	-	P74	Y6	T6	328 (3)
GND	-	P45	P66	P75	GND(4)	GND(4)	-
I/O	-	P46	P67	P76	W7	W6	331 (3)
I/O	-	P47	P68	P77	Y7	U7	334 (3)
I/O	P31	P48	P69	P78	V8	V7	337 (3)
I/O	P32	P49	P70	P79	W8	W7	340 (3)
VCC	-	-	P71	P80	VCC(4)	T7	-
I/O	-	-	P72	P81	Y8	W8	343 (3)
I/O	-	-	P73	P82	U9	U8	346 (3)
I/O	-	-	-	P84	Y9	W9	349 (3)
I/O	-	-	-	P85	W10	V9	352 (3)
I/O	P33	P50	P74	P86	V10	U9	355 (3)
I/O	P34	P51	P75	P87	Y10	T9	358 (3)
I/O	P35	P52	P76	P88	Y11	W10	361 (3)
I/O ($\overline{\text{INIT}}$)	P36	P53	P77	P89	W11	V10	364 (3)
VCC	P37	P54	P78	P90	VCC(4)	U10	-
GND	P38	P55	P79	P91	GND(4)	GND(4)	-
I/O	P39	P56	P80	P92	V11	T10	367 (3)
I/O	P40	P57	P81	P93	U11	R10	370 (3)
I/O	P41	P58	P82	P94	Y12	W11	373 (3)
I/O	P42	P59	P83	P95	W12	V11	376 (3)
I/O	-	-	P84	P96	V12	U11	379 (3)

XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280(2,5)	Bndry Scan
O, TDO	P157	P181	A19	B17	0
GND	P158	P182	GND(4)	GND(4)	-
I/O	P159	P183	B18	A18	2
I/O, PGCK4(1), GCK7(2)	P160	P184	B17	A17	5
I/O	P161	P185	C17	D16	8
I/O	P162	P186	D16	C16	11
I/O (CS1(2))	P163	P187	A18	B16	14
I/O	P164	P188	A17	A16	17
I/O	-	-	-	E15	20
I/O	-	-	-	C15	23
I/O	P165	P189	C16	D15	26
I/O	-	P190	B16	A15	29
I/O	P166	P191	A16	E14	32
I/O	P167	P192	C15	C14	35
I/O	P168	P193	B15	B14	38
I/O	P169	P194	A15	D14	41
GND	P170	P196	GND(4)	GND(4)	-
I/O	P171	P197	B14	A14	44
I/O	P172	P198	A14	C13	47
I/O	-	P199	C13	B13	50
I/O	-	P200	B13	A13	53
VCC	P173	P201	VCC(4)	VCC(4)	-
I/O	-	-	A13	A12	56
I/O	-	-	D12	C12	59
I/O	P174	P202	C12	B12	62
I/O	P175	P203	B12	D12	65
I/O	P176	P205	A12	A11	68
I/O	P177	P206	B11	B11	71
I/O	P178	P207	C11	C11	74
I/O	P179	P208	A11	D11	77
I/O	P180	P209	A10	A10	80
I/O	P181	P210	B10	B10	83
GND	P182	P211	GND(4)	GND(4)	-

2/8/00

Notes:
1. 5V Spartan family only
2. 3V Spartan-XL family only
3. The “PWRDWN” on the XCS40XL is not part of the Boundary Scan chain. For the XCS40XL, subtract 1 from all Boundary Scan numbers from GCK3 on (343 and higher).
4. Pads labeled GND(4) or V_{CC}(4) are internally bonded to Ground or V_{CC} planes within the package.
5. CS280 package discontinued by PDN2004-01

Additional XCS40/XL Package Pins

PQ240

GND Pins					
P22	P37	P83	P98	P143	P158
P204	P219	-	-	-	-
Not Connected Pins					
P195	-	-	-	-	-

2/12/98

BG256

VCC Pins					
C14	D6	D7	D11	D14	D15
E20	F1	F4	F17	G4	G17
K4	L17	P4	P17	P19	R2
R4	R17	U6	U7	U10	U14
U15	V7	W20	-	-	-
GND Pins					
A1	B7	D4	D8	D13	D17
G20	H4	H17	N3	N4	N17
U4	U8	U13	U17	W14	-

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VCC Pins					
A1	A7	B5	B15	C10	C17
D13	E3	E18	G1	G19	K2
K17	M4	N16	R3	R18	T7
U3	U10	U17	V5	V15	W13
GND Pins					
E5	E7	E8	E9	E11	E12
E13	G5	G15	H5	H15	J5
J15	L5	L15	M5	M15	N5
N15	R7	R8	R9	R11	R12
R13	-	-	-	-	-

5/19/99